

ITW RCE 2814



**REQUEST  
FOR  
CONTINUED EXAMINATION (RCE)  
TRANSMITTAL**


Subsection (b) of 35 U.S.C. § 132, effective on May 29, 2000,  
provides for continued examination of an utility or plant application  
filed on or after June 8, 1995.  
See The American Inventors Protection Act of 1999 (AIPA).

Application Number	10/053,300
Filing Date	January 17, 2002
First Named Inventor	Vishnu K. Agarwal
Group Art Unit	2814
Examiner Name	Hoai Pham
Attorney Docket Number	303.780US1
Customer No.	21186

This is a Request for Continued Examination (RCE) under 37 CFR § 1.114 of the above-identified application entitled TRANSISTOR STRUCTURE HAVING REDUCED TRANSISTOR LEAKAGE ATTRIBUTES.

Submission required under 37 C.F.R. § 1.114

1. ☐ Consider the amendment(s)/reply under 37 C.F.R. § 1.116 previously filed on .
2. ☐ Consider the arguments in the Appeal Brief or Reply Brief previously filed on .
3. ☒ An Amendment ( 3 pages ) is enclosed.
4. ☐ A new power of attorney ( pages ) is enclosed.
5. ☒ An Information Disclosure Statement is enclosed ( 2 pages ).
  - a. 1 Form(s) 1449
  - b. 1 Copies of IDS Citations
6. ☐ A check in the amount of 0.00 is attached to pay the RCE filing fee required under C.F.R. § 1.17(e).
7. ☒ **The Commissioner is hereby authorized to credit overpayments or charge any fees set forth in 37 CFR §§ 1.16 through 1.18 to Deposit Account No. 19-0743.**
8. ☐ A Petition for Extension of Time in the prior application ( pages ) is enclosed along with a check in the amount of to pay the extension fee.
9. ☐ Others:  
SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

By:   
Atty: Suneel Arora  
Reg. No. 42,267  
Res. No. 40,957

12/22/2004 HALI11 00000054 190743 10053300  
01 FC:1801 790.00 DA

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Attn-Mail Stop RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 16 day of December, 2004.

Name



Signature



S/N10/053,300



PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Vishnu K. Agarwal et al. Examiner: Hoai Pham  
Serial No.: 10/053,300 Group Art Unit: 2814  
Filed: January 17, 2002 Docket No: 303.780US1  
Title: TRANSISTOR STRUCTURE HAVING REDUCED TRANSISTOR LEAKAGE  
ATTRIBUTES

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**AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

This Amendment is being filed along with a Request for Continued Examination. Please enter the following amendments.